

Electronic Patent Application Fee Transmittal

Application Number:	10748906			
Filing Date:	30-Dec-2003			
Title of Invention:	Semiconductor memory device testable with a single data rate and/or dual data rate pattern in a merged data input/output pin test mode			
First Named Inventor/Applicant Name:	Jong-Cheol Lee			
Filer:	Frank Chau/marg dougan			
Attorney Docket Number:	8836-223JHM/ID12244US			
Filed as Large Entity				
Utility Filing Fees				
Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Basic Filing:				
Pages:				
Claims:				
Miscellaneous-Filing:				
Petition:				
Patent-Appeals-and-Interference:				
Post-Allowance-and-Post-Issuance:				
Extension-of-Time:				

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Miscellaneous:				
Request for continued examination	1801	1	810	810
Total in USD (\$)				810